

<b>Notice of References Cited</b>	Application/Control No. 09/706,406	Applicant(s)/Patent Under Reexamination TAGG, JAMES P.	
	Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0132433	07-2004	Stern et al.	455/414.1
*	B	US-2002/0007407	01-2002	Klein, John Raymond	709/225
*	C	US-6,938,087	08-2005	Abu-Samaha, Mamoun	709/227
*	D	US-6,775,657	08-2004	Baker, Stephen M.	706/45
*	E	US-6,732,181	05-2004	Lim et al.	709/229
*	F	US-6,691,302	02-2004	Skrzynski et al.	717/118
*	G	US-6,915,345	07-2005	Tummala et al.	709/225
*	H	US-6,693,878	02-2004	Daruwalla et al.	370/235
*	I	US-6,608,832	08-2003	Forslow, Jan E.	370/353
*	J	US-6,289,462	09-2001	McNabb et al.	726/21
*	K	US-6,584,569	06-2003	Reshef et al.	726/25
*	L	US-6,522,880	02-2003	Verma et al.	455/436
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.